N-Channel Enhancement Mode Power MOSFET

Description

The HM75N06K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

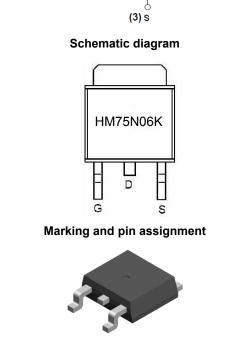
- $V_{DS} = 60V, I_D = 75A$ $R_{DS(ON)} < 11.5m\Omega @ V_{GS} = 10V$ (Typ:9.1m Ω)
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible Power Supply

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100% ΔVds TESTED!



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TO-252-2L top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM75N06K	HM75N06K	TO-252-2L	-	-	-

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	60	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	Ι _D	75	А
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	50	А
Pulsed Drain Current	I _{DM}	300	А
Maximum Power Dissipation	PD	110	W
Derating factor		0.73	W/℃
Single pulse avalanche energy (Note 5)	E _{AS}	450	mJ
Operating Junction and Storage Temperature Range	T_J,T_STG	-55 To 175	°C

Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 2)	R _{eJC}	1.36	°C /W	
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Electrical Characteristics (T_c=25°C unless otherwise noted)

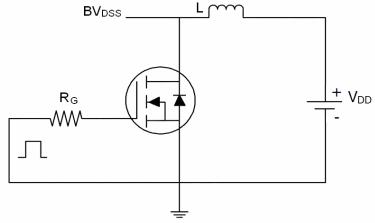
Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	60	68	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =60V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	2	3	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =30A	-	9.1	11.5	mΩ
Forward Transconductance	g fs	V _{DS} =25V,I _D =30A	20	-	-	S
Dynamic Characteristics (Note4)	·		•			
Input Capacitance	C _{lss}		-	2350	-	PF
Output Capacitance	C _{oss}	$V_{DS}=25V, V_{GS}=0V,$	-	237	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	205	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	16	-	nS
Turn-on Rise Time	tr	V _{DD} =30V,I _D =2A,R _L =15Ω	-	10	-	nS
Turn-Off Delay Time	t _{d(off)}	V _{GS} =10V,R _G =2.5Ω	-	45	-	nS
Turn-Off Fall Time	t _f		-	12	-	nS
Total Gate Charge	Qg	N/ 201/1 20A	-	50	-	nC
Gate-Source Charge	Q _{gs}	V_{DS} =30V,I _D =30A,	-	12	-	nC
Gate-Drain Charge	Q _{gd}	V _{GS} =10V	-	16	-	nC
Drain-Source Diode Characteristics					L	
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =30A	-	-	1.2	V
Diode Forward Current (Note 2)	I _S		-	-	75	A
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF =75A	-	28		nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs(Note3) - 49		nC		
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				y LS+LD)

Notes:

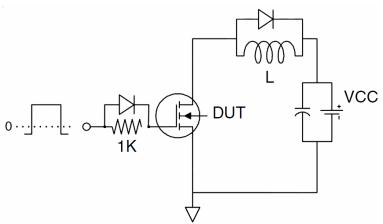
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- 5. E_{AS} condition : Tj=25°C, V_{DD}=30V, V_G=10V, L=0.5mH, Rg=25\Omega

Test Circuit

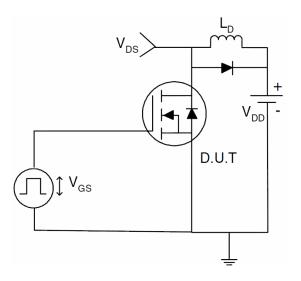
1) E_{AS} test Circuit

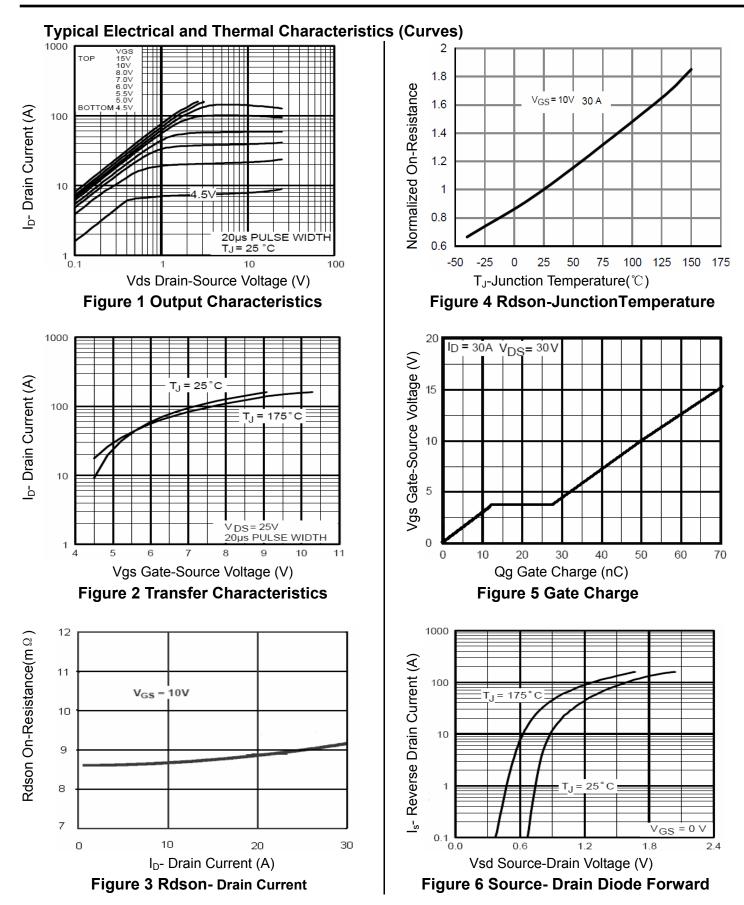


2) Gate charge test Circuit



3) Switch Time Test Circuit

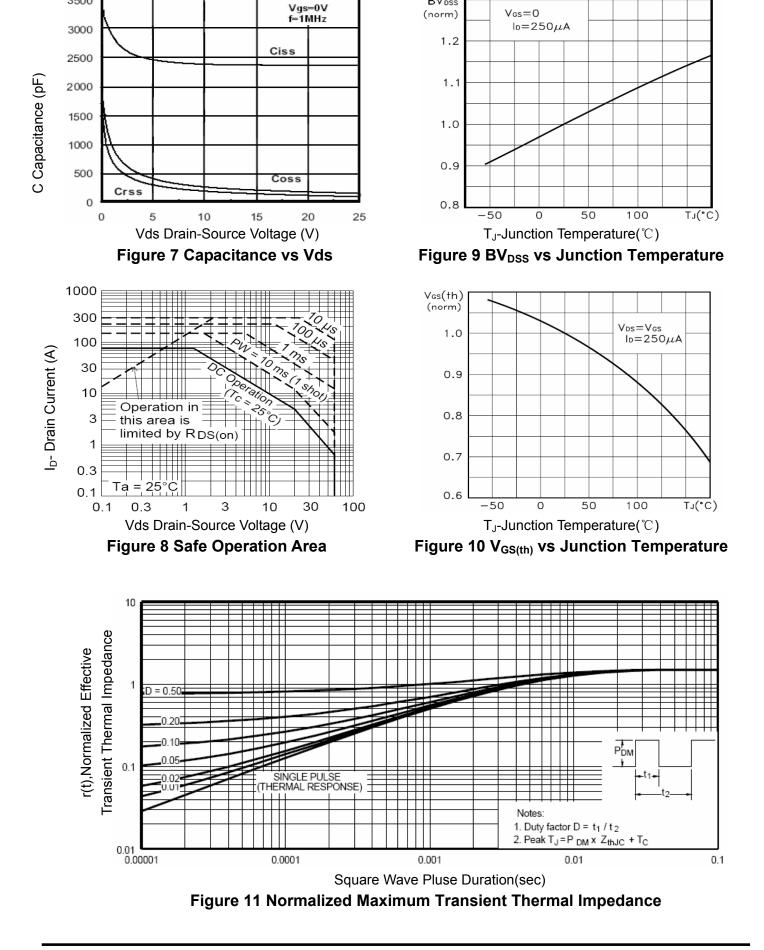






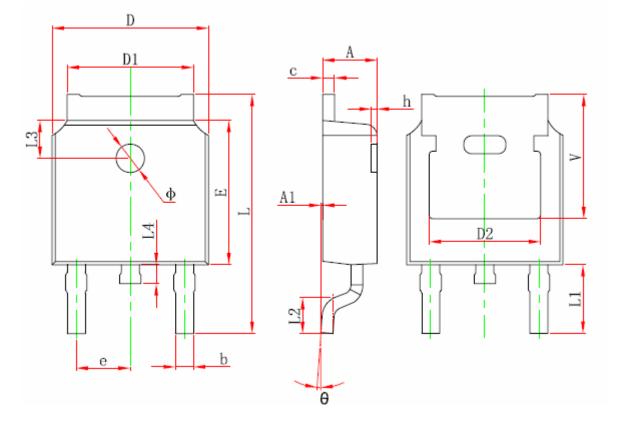
3500

HM75N06K



BVDSS

TO-252-2L Package Information



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
A	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
с	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830	REF.	0.190 REF.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900	REF.	0.114 REF.		
L2	1.400	1.700	0.055	0.067	
L3	1.600	REF.	REF.		
L4	0.600	1.000	0.024	0.039	
Φ	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350	REF.	0.211 REF.		

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